Contribution ID: 14

Noise Performance in CMOS Devices

Wednesday, 5 August 2009 15:10 (20 minutes)

Submicrometer CMOS technologies provide well-established solutions to the implementation of low-noise front-end electronic for a wide range of applications including detector applications. This paper briefly discusses submicron transistor technologies, the setup necessary for measuring noise in transistors and reason for this measurement.

 Primary author:
 WINJOBI, Ifeoluwa (Benedict College)

 Presenter:
 WINJOBI, Ifeoluwa (Benedict College)